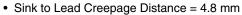


# N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	100			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	0.086		
Q <sub>g</sub> (Max.) (nC)	72			
Q <sub>gs</sub> (nC)	11			
Q <sub>gd</sub> (nC)	32			
Configuration	Single			

#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz

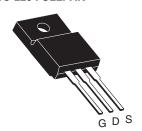


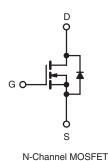
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available





#### **TO-220 FULLPAK**





PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	$V_{DS}$	100	v		
Gate-Source Voltage	$V_{GS}$	± 20	1 V		
Continuous Drain Current	$V_{GS}$ at 10 V $T_C = 25 ^{\circ}C$	I-	18	А	
	$V_{GS}$ at 10 $V_{C} = 100 ^{\circ}C$	I <sub>D</sub>	12		
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>	68			
Linear Derating Factor		0.32	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	720	mJ		
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	17	Α		
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	4.8	mJ		
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	$P_{D}$	48	W	
Peak Diode Recovery dV/dtc	dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>	1	
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-32 OF IVIS SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ ,  $L = 3.7 \,\text{mH}$ ,  $R_G = 25 \,\Omega$ ,  $I_{AS} = 17 \,\text{A}$  (see fig. 12). c.  $I_{SD} \le 17 \,\text{A}$ ,  $dI/dt \le 200 \,\text{A}/\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \,^{\circ}\text{C}$ .
- d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	$R_{thJA}$	-	65	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	3.1	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	100	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.13	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		1.0	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	,	V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zara Oaka Walkara B. 1. O 1	ate Voltage Drain Current $I_{DSS} = V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 150 \text{ V}$	V <sub>DS</sub> =	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V		-	25	μΑ
Zero Gate Voltage Drain Current		, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	250		
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A <sup>b</sup>	-	0.086	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 10 A <sup>b</sup>		9.1	-	-	S
Dynamic					•	•	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$ $f = 1.0 \text{ MHz}$		-	1700	-	- pF
Output Capacitance	C <sub>oss</sub>			-	560	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	120	-	
Drain to Sink Capacitance	С			-	12	-	
Total Gate Charge	Qg	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 17 A, V <sub>DS</sub> = 80 V, see fig. 6 and 13 <sup>b</sup>	-	-	72	nC
Gate-Source Charge	Q <sub>gs</sub>			-	-	11	
Gate-Drain Charge	Q <sub>gd</sub>	1		-	-	32	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 50 \text{ V}, I_D = 17 \text{ A},$ $R_G = 9.1 \Omega, R_D = 2.9 \Omega,$ see fig. $10^b$		-	11	-	- ns
Rise Time	t <sub>r</sub>			-	44	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-	
Fall Time	t <sub>f</sub>			-	43	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	
Drain-Source Body Diode Characteristic	s						•
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	68	
Body Diode Voltage	$V_{SD}$	$T_J = 25$ °C, $I_S = 17$ A, $V_{GS} = 0$ V <sup>b</sup>		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = 17 A, dl/dt = 100 A/μs <sup>b</sup>		-	180	360	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	1.3	2.6	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and				$L_S$ and I	_D)

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu s;$  duty cycle  $\leq$  2 %.



### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

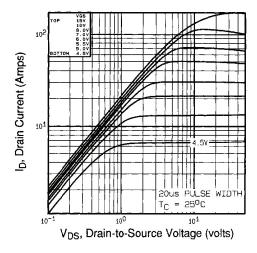


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

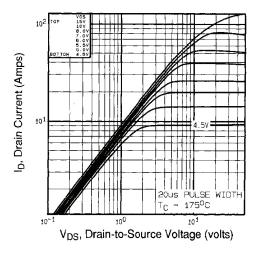


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

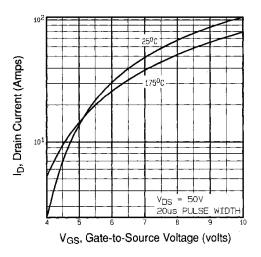


Fig. 3 - Typical Transfer Characteristics

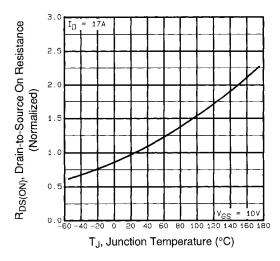


Fig. 4 - Normalized On-Resistance vs. Temperature



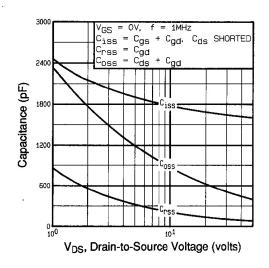


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

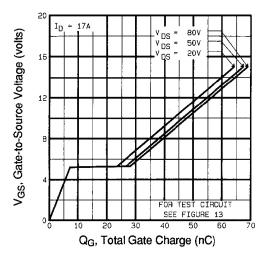


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

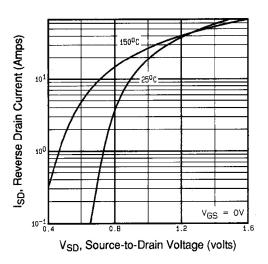


Fig. 7 - Typical Source-Drain Diode Forward Voltage

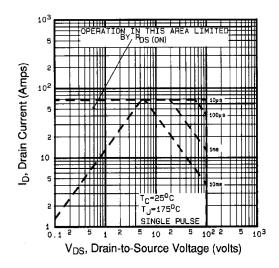


Fig. 8 - Maximum Safe Operating Area



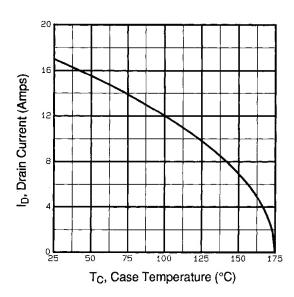


Fig. 9 - Maximum Drain Current vs. Case Temperature

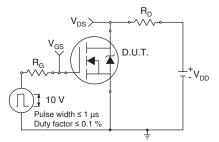


Fig. 10a - Switching Time Test Circuit

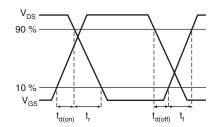


Fig. 10b - Switching Time Waveforms

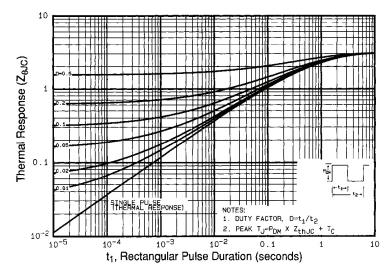


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

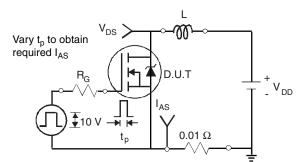


Fig. 12a - Unclamped Inductive Test Circuit

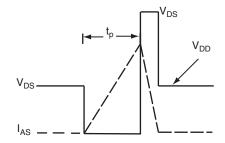


Fig. 12b - Unclamped Inductive Waveforms



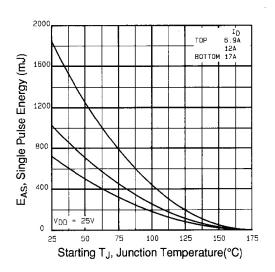


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

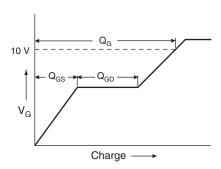


Fig. 13a - Basic Gate Charge Waveform

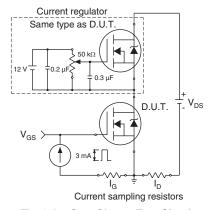
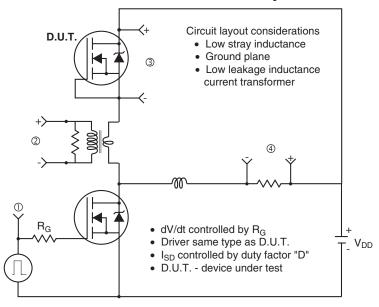
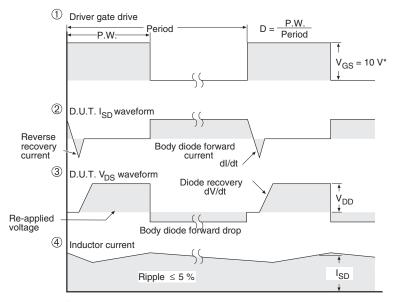


Fig. 13b - Gate Charge Test Circuit



### Peak Diode Recovery dV/dt Test Circuit





\*  $V_{GS} = 5 V$  for logic level devices

Fig.14 - For N-Channel



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